## Notice of References Cited Application/Control No. 10/608,093 Examiner TRUNG DIEP Applicant(s)/Patent Under Reexamination WATANABE ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,646,677 B2	11-2003	Noro et al.	348/156
*	В	US-6,356,303 B1	03-2002	Shibata et al.	348/211.1
*	С	US-6,961,082 B2	11-2005	Miura et al.	348/211.9
*	D	US-6,313,875 B1	11-2001	Suga et al.	348/211.99
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.